






Minseung Ahn, Ph.D.

Technology Specialist, Patent Agent

 Washington, D.C.

 202-626-7708

 ahn@fr.com

Overview

About Minseung

Minseung Ahn, Ph.D., is a technology specialist and patent agent in the Washington, D.C., office of Fish & Richardson P.C. Dr. Ahn's practice supports the preparation and prosecution in the areas of mechanical engineering, electrical and computer technology, semiconductor processing and devices, and software. Prior to joining the firm, Dr. Ahn worked at Intel Corp., where he developed next-generation CPU and SoC products. Dr. Ahn also has extensive research and industry experience in mechanical engineering, semiconductor equipment, control systems, optical instruments, haptics, MEMS, and nanotechnology.

Focus Areas

Services

- Patent

Industries

- Electrical and Computer Technology
- Manufacturing
- Nanotechnology
- Optics
- Semiconductors
- Software

Education

Ph.D., Mechanical Engineering, Massachusetts Institute of Technology (2009)

M.S., Mechanical Engineering, Massachusetts Institute of Technology (2005)

B.S., Mechanical and Aerospace Engineering, Seoul National University (1999)

Insights

Selected Publications

M. Ahn, R. Heilmann, M. Schattenburg, "Fabrication of ultra-high aspect-ratio freestanding gratings on silicon-on-insulator wafers," J. Vac. Sci. Technol. B 25, Nov/Dec 2007.

M. Ahn, R. Heilmann, M. Schattenburg, "Fabrication of 200 nm-period blazed transmission gratings on silicon-on-insulator wafers," J. Vac. Sci. Technol. B, Nov/Dec 2008.

R. Heilmann, M. Ahn, E. Gullikson, M. Schattenburg "Blazed high-efficiency x-ray diffraction via transmission through arrays of nanometer-scale mirrors ," Optics Express 16, June 2008.

D. L. Voronov, M. Ahn, E. H. Anderson, et al. "High Efficiency 5000 Lines/mm Multilayer-Coated

Blazed Grating for Extreme Ultraviolet Wavelengths,” Opt. Lett. 35, 2010.

R. K. Heilmann, M. Ahn, A. Bruccoleri, et al. “Diffraction Efficiency of 200 nm Period Critical-Angle Transmission Gratings in the Soft X-Ray and Extreme Ultraviolet Wavelength Bands,” Appl. Opt. 50, 2011.

Languages

- English
- Korean